

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/640,988	LUECK ET AL.	
Examiner	Art Unit	
Kim T Huynh	2112	

	SEAR	CHED	
Class	Subclass	Date	Examiner
710	107	9/30/2005	кн
710	240-244	9/30/2005	КН
710	305-306	9/30/2005	КН
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
710	306, 107	7/21/2006	КН		
710	240	7/21/2006	кн		

SEARCH NO (INCLUDING SEARCH	TES I STRATEGY)
	DATE	EXMR
East search uspat, uspgpub,epo, jpo, derwent	9/30/2005	КН
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